

**Notice of References Cited**

Application/Control No.

09/755,489

Applicant(s)/Patent Under  
Reexamination  
LIN ET AL.

Examiner

Edwin A. León

Art Unit

2833

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*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
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**NON-PATENT DOCUMENTS**

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